# Harden Deep Neural Networks Against Fault Injections Through Weight Scaling

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Abstract-Deep neural networks (DNNs) have enabled smart applications on hardware devices. However, these hardware devices are vuinerable to unintended faults caused by aging, temper-ature variance, and write errors. These faults can cause bit-flips in DNN weights and significantly degrade the performance of DNNs. Thus, protection against these faults is crucial for the deployment of DNNs in critical applications. Previous works have proposed error correction codes based methods, however these methods often require high overheads in both memory and computation. In this paper, we propose a simple yet effective method to harden real temper-DNN weights by multiplying weights by constants before storing them to fault-prone medium. When used, these weights are divided back by the same constant. method is based on the observation that errors from Dit-mps have properties similar to additive noise, therefore by dividing by constants can reduce the absolute error from bit-flips. To demonstrate our method, we conduct experiments across four ImageNet 2012 pre-trained models along with three different data types: 32-bit floating point, 16-bit floating point, and 8-bit fixed point. This method demonstrates that by only multiplying weights with constants, Top-1 Accuracy of 8-bit fixed point ResNet50 is improved by 54.418 at bit-error rate of 0.0001. Index Terms—Deep Learning, Fault-tolerance, Resilience I. INTRODUCTION In recent years, deep neural networks (DNNs) have enabled applications such as image recognition [1], object detection [2], and natural language processing [3]. These applications form the backbones of many critical systems, including autonomous cars [4], healthcare [5], and more. However, as DNNs are deployed to hardware devices, they become vulnerable to fault injection, which can be caused by aging [6], temperature variance [7], and write errors [8]. These faults can manifest as bit-flips to DNN weights and can easily degrade DNN performances [9]. Without any protections, faults occurring in DNNs used in critical applications may lead to back by the same constants to restore the original scale. Our method is based on the observation that errors from bit-flips

serious consequences.

To address this issue, several research directions have been proposed. One of the research directions is error-correction code (ECC) based methods [10]-[13], which use ECC to encode redundancy in the form of additional bits to DNN parameters and enable ECC to correct a certain number of bit-flips. However, these methods often require high overheads

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in both memory to encode redundancy and computation to locate and correct error bits. The works in this direction [10]-[12] explore weight parameter characteristics to reduce memory overheads; however, the computational overheads still remain high.

In this paper, our work proposes a simple yet efficient method that requires only element-wise multiplication before writing and element-wise division after reading weights from faultprone mediums. We demonstrate that these processes reduce the overall absolute error caused by bit-flips. Furthermore, we propose a method that reduces the overall number of divisions by dividing output logits instead of weights. We show that our method can be applied across three data types: 32-bit floating point (FP32), 16-bit floating point (FP16), and 8-bit fixed point (Q2.5, with 1-bit sign, 2-bit integer, and 5-bit fraction). An overview of our proposed method is illustrated in Fig. 1.

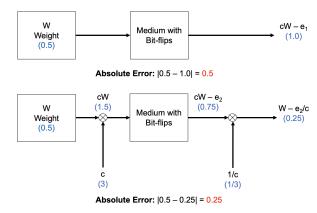


Fig. 1: Overview of our proposed method. Top: illustrates the baseline method, where a weight W is directly written to faultprone mediums. When read, this weight is affected by bitflip errors in the form of  $e_1$ . Bottom: illustrates our proposed method, where a weight W is multiplied by a constant c before being written to fault-prone mediums. During deployment, the weights with faults  $cW - e_2$  are read and rescaled back to the original scale  $W - \frac{e_2}{c}$ . By scaling and rescaling the weights, the overall absolute error caused by bit-flips is reduced. In this example, a bit-flip is injected into the 9-th bit position (1-th bit position is a sign bit) of the FP32 weight.

Our main contributions are listed as follows:

This research is based on results obtained from a project, JPNP16007, commissioned by the New Energy and Industrial Technology Development Organization (NEDO).

- This work demonstrates that simple element-wise multiplications and divisions can improve the robustness of DNNs against bit-flips.
- This work shows that our proposed method can be generalized across four ImageNet 2012 pre-trained models and three data types.
- This work proposes a method to reduce the number of divisions by dividing output logits instead of weights.

# II. RELATED WORKS

This section discusses works related to hardening DNNs against fault injections. One approach to protecting DNNs against bit-flips is to use ECC. ECC encodes redundancy in the form of parity bits to DNN parameters, allowing it to correct a certain number of bit-flips in the parameters. However, storing parity bits requires additional memory, so ECC-based methods often focus on reducing memory overheads by exploiting weight distribution characteristics.

Following this direction, in-place zero-space memory protection [12] is designed using ECC, specifically the extended Hamming code (64, 57), which can correct up to one bitflip error. This method also proposes a training strategy that penalizes large weights, ensuring that large weights appear only at specific positions. This approach ensures that most weights small, making the most significant bits (MSB) after the sign bit likely to hold no information. As a result, this bit position can be used to insert a parity bit.

In the same direction, value-aware parity insertion ECC [11] is a method based on ECC (64, 50), which can correct double bit-flips. This method is designed for Q2.5 DNNs. To reduce memory overheads, it leverages the observation that the most weight values are less than |0.5|, meaning the first two integer bits are likely to hold no information. As a result, these bit positions can be used to insert parity bits. If the weight values are greater than or equal to |0.5|, the last two least significant bits (LSB) are used for parity bit insertion instead, ensuring minimal information loss.

In another approach, instead of protecting all bit positions equally, efficient repetition code for deep learning [10] is designed to protect only the bit positions close to the MSB, while avoiding protection for the bit positions near the LSB. This approach is based on the observation that bit-flips in bit positions near the MSB can cause dramatic changes compared to those near the LSB. Therefore, these bit positions near the MSB are prioritized for protection.

ECC-based approaches are similar to our method, as both exploit the characteristics of weight parameters and modify them either by inserting parity bits or scaling. A key distinction is that our method incurs significantly lower computational overhead compared to ECC-based methods. Our method only requires only element-wise multiplication and division, whereas ECC-based methods involve encoding and decoding processes that can be computationally expensive.

#### **III. PRELIMINARIES**

In this section, we describe the prerequisites for our proposed method. Given a i-th layer and j-th DNN weight denoted

as  $W_{i,j} \in \mathbb{R}$ , its binary representation is denoted as  $B_{i,j} \in \{0,1\}^n$ , where *n* is the number of bits of the data type. Here,  $B_{i,j,1}$  denotes the MSB, and  $B_{i,j,n}$  denotes the LSB.

To model fault injections, a bit-flip at  $B_{i,j,k}$  is defined as  $M_{i,j,k} \in \{0,1\}$ , where  $M_{i,j,k} = 1$  indicates the presence of a bit-flip, while  $M_{i,j,k} = 0$  indicates no bit-flip. The probability of  $M_{i,j,k}$  is defined in (1), where BER is the bit-error rate, or probability of a bit-flip.

$$P(M_{i,j,k}) = \begin{cases} BER & \text{if } M_{i,j,k} = 1\\ 1 - BER & \text{if } M_{i,j,k} = 0 \end{cases}$$
(1)

To model bit-flip errors, let  $f_D$  be a function that converts a binary representation to its data type D and let  $b_D$  be a function that converts a data type D to its binary representation, where  $D \in \{FP32, FP16, Q2.5\}$ . Therefore, the *i*-th layer and *j*-th weight with bit-flips, denoted as  $\hat{W}_{i,j}$ , is defined in (2), where  $M_{i,j}$  is a bit-flip mask representing bit-flip occurrences for the weight at indices *i* and *j*.

$$\hat{W}_{i,j} = f_D(b_D(W_{i,j}) \oplus M_{i,j}) \tag{2}$$

Errors from bit-flip are founded using e function defined in (3), where  $\oplus$  denotes as an element-wise XOR operation.

$$e(W_{i,j}, M_{i,j}) = W_{i,j} - f_D(b_D(W_{i,j}) \oplus M_{i,j})$$
  
=  $W_{i,j} - \hat{W}_{i,j}$  (3)

# IV. PROPOSED METHODS

After describing the prerequisites, we present our proposed method to harden DNNs against fault injections through weight scaling in this section. Our method scales the weights  $W_i$  by  $c_i$  before passing them to the *e* function that injects bit-flips into  $c_i W_i$ . After that, the weights are rescaled by dividing by the same  $c_i$ .

# A. FP32 and FP16 Requirements

To enable FP32 and FP16 models to operate with faults, it is necessary to avoid bit-flips to the most significant bit of the exponent term or ensure  $M_{i,j,2} = 0$ . A bit-flip in this position can significantly alter the magnitude of the weight. For example, 0.1 can be changed to  $\approx 3.403 \times 10^{37}$ , and 1.0 can be changed to Infinity (Inf).

To enable this assumption, either ECC can be used to ensure data integrity, or values can be clamped to a range of (-2, 2), based on the observation that well-trained weights are typically small values [11], [12]. From our observations, only two weights from torchvision [14] pre-trained weights—from AlexNet [15], ResNet18 [16], ResNet50 [16], and DenseNet169 [17] models—fall outside this range (-2, 2). For example, clamping AlexNet weights to this range results in a minor accuracy drop from 57.55 to 56.50. When all weights are within this range, we can assume that the MSB of exponent term is always zero.

To enable this assumption in a lossless manner, a sparse matrix method based on [11] can be used to store the positions of values that fall outside the range of (-2, 2). Since the

majority of weight values are within that range, the overhead of this method should be minimal. By ensuring that the sparse matrix remains lossless, weights outside the (-2, 2) can be reincorporated into the model later.

Enabling this assumption makes FP32 and FP16 models more robust compared to Q2.5 models. While this assumption may introduce additional overhead, it is important to note that our method with Q2.5 does not require it.

# B. Scaling, Rescaling, and Their Effects

Before deployment to fault-prone mediums, the *i*-th layer weight  $W_i$  is scaled by a constant  $c_i$ , then written to the fault-prone mediums, as shown in (4). The weights with faults, based on our proposed method, are denoted as  $\tilde{W}_{i,j}$ .

$$c_i \tilde{W}_{i,j} = c_i W_{i,j} - e(c_i W_{i,j}, M_{i,j})$$
(4)

After receiving the scaled weight with fault injections, it can be recovered by dividing by  $c_i$ , as shown in (5),

$$\tilde{W}_{i,j} = W_{i,j} - \frac{e(c_i W_{i,j}, M_{i,j})}{c_i}$$
(5)

From our observations, the *e* function is not scale-invariant, meaning that  $e(c_iW_{i,j}, M_{i,j}) \neq c_ie(W_{i,j}, M_{i,j})$ . When  $c_i > 1$ , after scaling  $W_{i,j}$  with  $c_i$ , we found that, on average, bit-flips to scaled weights cause higher absolute error from bit-flips:  $|e(c_iW_{i,j}, M_{i,j})| > |e(W_{i,j}, M_{i,j})|$ . However, after rescaling back to the original scale, the absolute error from bit-flips is reduced:  $|\frac{e(c_iW_{i,j}, M_{i,j})|}{c_i}| < |e(W_{i,j}, M_{i,j})|$ . These observations are based on the following analysis.

# C. Analysis of the Effects of Scaling and Rescaling

In this analysis, pseudo-weights were generated from -0.5 to 0.5 with an increment of 0.01. This range is chosen based on [11], which indicates that the most of pre-trained weights from certain models fall within this interval.

Monte Carlo simulations were conducted for  $10^6$  rounds by randomly injecting bit-flips into pseudo-weights with a  $BER = 10^{-1}$ . This analysis was performed across several values of  $c_i$ . Note that when  $c_i = 1$ , it represents the baseline method, without the use of our proposed method. Before injecting bitflips, weights are scaled by  $c_i$ , and after injecting bit-flips, the weights are rescaled back to the original scale by dividing by  $c_i$ . The absolute errors from bit-flips,  $|\frac{e(c_i W_{i,j}, M_{i,j})}{c_i}|$ , are averaged across simulations and presented in Fig. 2.

From Fig. 2, higher values of the constant  $c_i$  with our method result in lower overall absolute errors compared to the baseline. This holds true for  $c_i W_{i,j} \in (-2, 2)$  for FP32 and FP16 and  $c_i W_{i,j} \in [-2.0, 1.984375]$  for Q2.5.

For Q2.5, when the scaled weights  $c_iW_{i,j}$  exceed the Q2.5 data range of [-2, 1.984375] [18], overflow errors start to occur, as shown in "Proposed with c = 5.0" in Fig. 2c, where some of the scaled weights fall out of the range of [-2.0, 1.984375]. On the other hand, for FP32 and FP16, when the scaled weights  $c_iW_{i,j}$  exceed the range of (-2, 2) or when  $c_i \ge 4$ , our assumption that  $M_{i,j,2} = 0$  alone is insufficient to protect the models from drastic changes in the weights.

To further explain, when  $c_iW_{i,j} < 2$ , the exponent bits, or  $B_{i,j,2:9}$  are arranged in the form  $[0, X, X, ..., X]^T$ , where X indicates a "don't-care" term, and  $B_{i,j,a:b} = (B_{i,j,k})_{a \le k \le b}$ . However, when  $c_iW_{i,j} \ge 2$ ,  $B_{i,j,2:9} = [1, X, X, ..., X]^T$ . When bit-flips occur with  $c_iW_{i,j} < 2$ , the only vulnerable bit position that can lead to significant error is  $B_{i,j,2}$ , which is protected by our assumption. On the other hand, when  $c_iW_{i,j} \ge 2$ , these weights contain several vulnerable bit positions. For instance, if  $c_iW_{i,j} = 2$ , bit-flips in  $B_{i,j,3}$ ,  $B_{i,j,4}$ , and  $B_{i,j,5}$  can cause changes greater than or equal to 131,072.

We provide two hypothesises for how  $c_i > 1$  within given ranges helps reduce overall absolute errors. The first hypothesis is that  $e(c_i W_{i,j}, M_{i,j})$  grows more slower than  $c_i e(W_{i,j}, M_{i,j})$ , meaning that dividing by  $c_i$  reduces the absolute error from bitflips. The second hypothesis is that  $e(c_i W_{i,j}, M_{i,j})$  behaves similarly to additive noise, so dividing by  $c_i$  reduces the absolute error from bit-flips.

# D. Finding the Optimal $c_i$

To find the optimal  $c_i$ , based on our analysis, the highest possible  $c_i$  that scales  $W_i$  into the range (-2, 2) for FP32 and FP16, or [-2, 1.984375] for Q2.5, must be determined. Since  $W_i$  varies across layers, t is defined as the maximum value to which  $W_i$  can be scaled. For FP32 and FP16, t = 1.9999 is selected, and for Q2.5, t = 1.97 is chosen instead of 1.984375 to avoid rounding issues. The optimal  $c_i$  is founded by (6).

$$c_i = \frac{t}{\max(|W_i|)} \tag{6}$$

#### V. EXPERIMENTAL RESULTS AND DISCUSSION

In this paper, we conducted three experiments: fault injection with ResNet18 across different BERs, fault injection across models, and a demonstration of how to reduce the overall divisions by dividing output logits instead of weights.

# A. Fault Injection Across Different BERs

In this experiment, we conducted fault injections with ResNet18 across different BERs and t values. Our ResNet18 weights were retrieved from torchvision package [14]. For FP16 and Q2.5, the FP32 weights were converted to their respective data types. All DNN operations were still performed using FP32 data type, while the weights were simulated to experience bit-flips in their respective data types. For all experiments with FP32 and FP16, we assumed that no bit-flips occur in the MSB of the exponent term to ensure that the FP32 and FP16 models can operate under faults.

This experiment was designed to demonstrate how tinfluences the Top-1 Accuracy of ResNet18 BERvalues. We performed across different fault  $\{10^{-3}, \bar{10}^{-4}, 10^{-5}\}$ injections with BER $\in$ and  $t \in \{0.5, 1.0, 1.5, 1.9999, 2.5, 3.0, 3.5, 4.0\}$  for FP32 and FP16. For Q2.5, we used the same BER values but with t $\in$  $\{0.5, 1.0, 1.5, 1.97, 2.5, 3.0, 3.5, 4.0\}$ . Monte Carlo simulations were conducted to inject bit-flips into the weights, with 10 rounds for each BER and t.

The experimental results are visualized in Fig. 3, with error bars indicating the standard deviation. The results are consistent

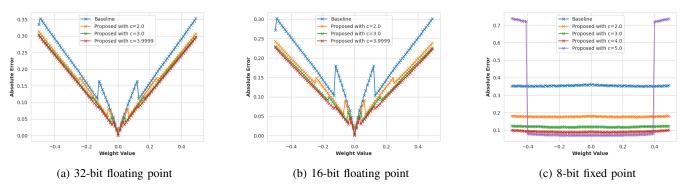


Fig. 2: Absolute errors caused by bit-flips across three data types, comparing the baseline method and our proposed method.

with our analysis, showing that our proposed method achieves the highest Top-1 Accuracy when t = 1.9999 for FP32 and FP16, and t = 1.97 for Q2.5. When t > 1.9999 for FP32 and FP16, and t > 1.97 for Q2.5, the Top-1 Accuracies drop significantly, and the error bars increase due to more vulnerable bit positions for FP32 and FP16, as well as overflow errors for Q2.5.

## B. Fault Injection Across Models

In this experiment, we injected faults or bit-flips into ImageNet 2012 [19] pre-trained models: AlexNet [15], ResNet18 [16], ResNet50 [16], and DenseNet169 [17]. These pre-trained weights were retrieved from the torchvision package [14]. We performed 10 rounds of Monte Carlo simulations to inject bit-flips into weights and reported the average Top-1 Accuracy with standard deviation, in format of Top-1 Accuracy  $\pm$ Standard Deviation. Before the experiments, the original Top-1 Accuracy of these models, or baseline scores without bit-flips, were reported as shown in Table I.

TABLE I: The original Top-1 Accuracy of the models without bit-flips across the three data types.

Model	Datatype	Original Top1 Acc (%)
AlexNet	FP32	56.55
	FP16	56.55
	Q2.5	51.24
ResNet18	FP32	69.76
	FP16	69.75
	Q2.5	66.87
ResNet50	FP32	76.15
	FP16	76.15
	Q2.5	72.26
DenseNet169	FP32	75.59
	FP16	75.6
	Q2.5	71.81

Monte Carlo simulations were performed with  $BER = 10^{-3}$  for FP32 and FP16, and  $BER = 10^{-4}$  for Q2.5. A higher BER was applied for FP32 and FP16 because higher model failure rates were observed for Q2.5 at  $BER = 10^{-3}$ . Following the optimal t values from the previous experiment, t = 1.9999 was used for FP32 and FP16, and t = 1.97 for Q2.5. The experimental results are presented in Table II.

TABLE II: Models under fault injection across three data types with different t values.

Model	Datatype	t	<b>Top1 Acc (%)</b>
AlexNet	FP32	1.0	$2.68 \pm 1.44$
	FP32	1.9999	$34.26 \pm 5.27$
ResNet18	FP32	1.0	$14.78 \pm 7.04$
	FP32	1.9999	$53.29 \pm 4.62$
ResNet50	FP32	1.0	$4.83 \pm 4.01$
	FP32	1.9999	$53.78 \pm 9.30$
DenseNet169	FP32	1.0	$7.02 \pm 4.45$
	FP32	1.9999	$56.67 \pm 4.67$
AlexNet	FP16	1.0	$2.83 \pm 1.27$
	FP16	1.9999	$\textbf{32.40} \pm \textbf{4.72}$
ResNet18	FP16	1.0	$23.48 \pm 5.80$
	FP16	1.9999	$56.34 \pm 3.00$
ResNet50	FP16	1.0	$4.43 \pm 4.33$
	FP16	1.9999	59.87 ± 4.62
DenseNet169	FP16	1.0	$3.85 \pm 2.08$
	FP16	1.9999	$58.59 \pm 6.57$
AlexNet	Q2.5	1.0	$6.35 \pm 3.46$
	Q2.5	1.97	$\textbf{38.18} \pm \textbf{4.35}$
ResNet18	Q2.5	1.0	$32.59 \pm 10.28$
	Q2.5	1.97	$63.88 \pm 2.20$
ResNet50	Q2.5	1.0	$14.38 \pm 6.02$
	Q2.5	1.97	$68.80 \pm 2.55$
DenseNet169	Q2.5	1.0	$16.02 \pm 8.97$
	Q2.5	1.97	67.97 ± 3.45

From Table II, at  $BER = 10^{-3}$ , FP16 is overall more resilient to bit-flips compared to FP32. We observe that our proposed method with the optimal t improves the Top-1 Accuracy across all models and data types. On average, the Top-1 Accuracy of models with bit-flips is improved by 42.17 for FP32, 43.15 for FP16, and 42.37 for Q2.5 by simply multiplying and dividing weights with constants.

# C. Reducing Division Overhead

Our proposed method requires dividing the weights  $W_i$  by  $c_i$  after reading from fault-prone mediums. Since this division operation can be computationally expensive and it must be applied to all n weight parameters, we propose a method that reduces the number of divisions by performing the divisions only at the output logits, as illustrated in Fig. 4.

Instead of dividing the weights immediately after reading them from fault-prone mediums, Fig. 4 shows that DNN oper-

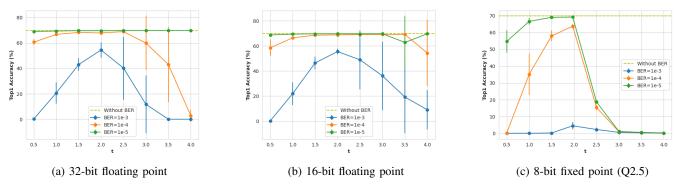


Fig. 3: Top-1 Accuracy of ResNet18 under various BER values and different t.

ations can be performed without division, or with  $W_i$  scaled by  $c_i$ . This method requires data types with a wide dynamic range, such as floating point, particularly for operations involving higher magnitudes.

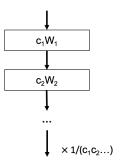


Fig. 4: Reduces the number of divisions by dividing the cumulative product of constants at the final logits, instead of dividing each weight and constant individually.

This method requires ab divisions, where a is the number of classes and b is the batch size. Our method is advantageous when a and b are small, or when ab < n. However, this method has two limitations. First, DNN operations must be performed at a higher magnitude region. where the precision of floating-point arithmetic is lower, potentially leading to a loss in precision. Second, while this method works with models using ReLU activation, it is not suitable for models with highly non-linear activation functions, such as Sigmoid or Tanh.

We conducted an experiment applying this method to FP32 AlexNet and obtained a Top-1 Accuracy of 54.13, compared to the original Top-1 Accuracy is 56.55 for FP32 AlexNet. We attribute the loss in Top-1 Accuracy to the precision issues inherent in floating point arithmetic.

# VI. CONCLUSION

In this paper, we propose a simple yet effective method to harden DNNs against bit-flips by multiplying DNN weights by layer-wise constants before passing them to noisy mediums. When using these weights, the weights with faults are divided by the same constants to return them to their original scales. With this approach, we demonstrate that, within certain ranges, the absolute errors from bit-flips can be reduced compared to the baseline. Furthermore, we propose a method to reduce the overall number of divisions by performing division only on the output logits, instead of on all weights.

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